

ABSTRACT

The invention relates to a sample support designed to support a sample which is to be detected and / or analysed by a photothermal detection method using an irradiation pump beam irradiating the sample and a
5 detection and / or analysis probe beam. It comprises a substrate supporting a stack of thin dielectric layers forming a Bragg mirror on which the sample will be supported, the stack of thin dielectric layers being used to reflect the pump beam that reaches it.

10 The invention also relates to a device for detection and / or analysis of a sample by a photothermal method, the said device comprising a sample support according to the invention, a means of lighting the sample supported by the said support and supplying a pump beam, a means of
15 detection and / or measurement of the absorption or reflection of the pump beam by the sample when it is illuminated by the said illumination means.

Finally, the invention relates to a particular application of the said device.

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No figure